Machine-Learning-Enabled Big Data Analysis: Advancements, Applications and Challenges

Guest Editor:

Dr. Mubeen Ghafoor
School of Computer Science, University of Lincoln, Lincoln LN6 7TS, UK

Deadline for manuscript submissions:
closed (31 March 2024)

Message from the Guest Editor

We cordially invite the academic community and relevant industry partners to submit original research articles and reviews to this Special Issue, with a specific focus on the following themes:

- Scalable machine learning algorithms for big data analysis;
- Deep learning architectures for processing and analyzing big data;
- Feature selection and dimensionality reduction techniques for big data analysis;
- Ensemble learning approaches for big data analysis;
- Big-data-enabled edge intelligence;
- Transfer learning methods for leveraging big data across domains;
- Privacy-preserving machine learning techniques for big data analysis;
- Explainable and interpretable machine learning models for big data analysis;
- Online and streaming algorithms for the real-time analysis of big data;
- Machine-learning-enabled video/VR data compression and analysis;
- Machine-learning-enabled analysis techniques for IoT data;
- Advanced tools and techniques for big data visualization;
- etc.

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, and other databases.
Journal Rank: JCR - Q2 (*Physics, Applied*) / CiteScore - Q2 (*Control and Systems Engineering*)

Contact Us